

TOSHIBA Field-Effect Transistor Silicon P-Channel MOS Type

SSM3J306T

Power management switch Applications

• 4 V drive

• Low ON-resistance: $R_{on} = 225 \text{ m}\Omega \text{ (max) } (@V_{GS} = -4 \text{ V})$

 $R_{on} = 117 \text{ m}\Omega \text{ (max) } (@V_{GS} = -10 \text{ V})$

Absolute Maximum Ratings (Ta = 25°C)

Characteristic		Symbol	Rating	Unit	
Drain-source voltage		V _{DS}	-30	V	
Gate-source voltage		V _{GSS}	± 20	V	
Drain current	DC	I _D	-2.4	А	
	Pulse	I _{DP}	-4.8		
Drain power dissipation		P _D (Note 1)	700	mW	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55 to 150	°C	

Note 1: Mounted on an FR4 board.

 $(25.4 \text{ mm} \times 25.4 \text{ mm} \times 1.6 \text{ t}, \text{ Cu Pad: } 645 \text{ mm}^2)$

Weight: 10 mg (typ.)

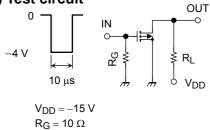
Electrical Characteristics (Ta = 25°C)

Charac	teristic	Symbol	Test Condition	Min	Тур.	Max	Unit
Drain–source breakdown voltage	V (BR) DSS	$I_D = -1 \text{ mA}, V_{GS} = 0$ -3	-30	_	_	٧	
	V (BR) DSX	$I_D = -1 \text{ mA}, V_{GS} = +20 \text{ V}$	-15	_	_		
Drain cutoff curren	t	I _{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0$	_	_	-1	μА
Gate leakage curre	ent	I _{GSS}	$V_{GS} = \pm 16 \text{ V}, V_{DS} = 0$	_	_	±1	μА
Gate threshold vol	tage	V _{th}	$V_{DS} = -5 \text{ V}, I_D = -1 \text{ mA}$	-1.2	_	-2.6	V
Forward transfer a	dmittance	Y _{fs}	$V_{DS} = -5 \text{ V}, I_{D} = -1 \text{ A}$ (Note 2)	1.6	3.1	_	S
Drain-source ON-resistance	R _{DS} (ON)	$I_D = -1 \text{ A}, V_{GS} = -10 \text{ V}$ (Note 2)	_	80	117	mΩ	
		$I_D = -0.5 \text{ A}, V_{GS} = -4 \text{ V}$ (Note 2)	_	160	225		
Input capacitance		C _{iss}		_	280	_	
Output capacitance Reverse transfer capacitance		C _{oss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0, f = 1 \text{ MHz}$	_	80	_	pF
		C _{rss}			45	_	
Total Gate Charge		Qg		_	2.5	_	
Gate-Source Charge		Q_{gs}	$V_{DS} = -15 \text{ V}, I_{DS} = -2.4 \text{ A}$	_	1.3	_	nC
Gate-Drain Charge)	Q_{gd}	V _{GS} = -4 V		1.2	_	
Switching time	Turn-on time	t _{on}	$V_{DD} = -15 \text{ V}, I_D = -1 \text{ A},$	_	16	_	ns
	Turn-off time	t _{off}	$V_{GS} = 0$ to -4 V, $R_G = 10 \Omega$		35	_	
Drain-source forward	ard voltage	V _{DSF}	$I_D = 2.4 \text{ A}, V_{GS} = 0 \text{ V}$ (Note	2) —	0.8	1.2	V

Note 2: Pulse test

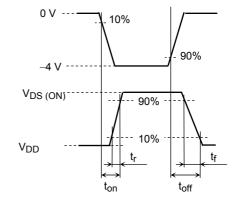
www.D Switching Time Test Circuit

(a) Test circuit



(b) V_{IN}

(c) Vout



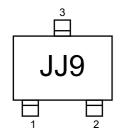
D.U. ≦ 1%

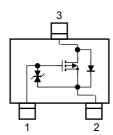
 $V_{IN}\!\!:\,t_r,\,t_f\!<\!5\;\text{ns}$ Common Source

 $Ta = 25^{\circ}C$

Marking

Equivalent Circuit (top view)





Precaution

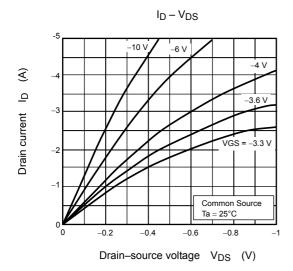
V_{th} can be expressed as the voltage between gate and source when the low operating current value is I_D = −1 mA for this product. For normal switching operation, VGS (on) requires a higher voltage than Vth and VGS (off) requires a lower voltage than V_{th}

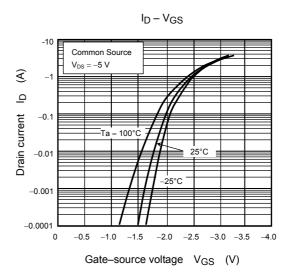
(The relationship can be established as follows: V_{GS (off)} < V_{th} < V_{GS (on).})

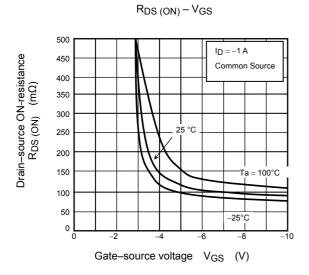
Take this into consideration when using the device.

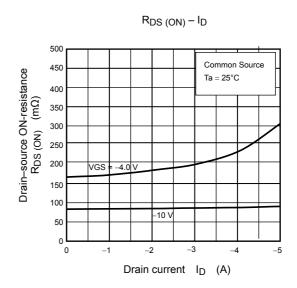
Handling Precaution

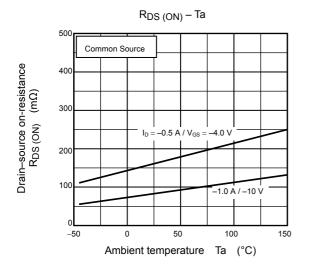
When handling individual devices that are not yet mounted on a circuit board, make sure that the environment is protected against electrostatic discharge. Operators should wear antistatic clothing, and containers and other objects that come into direct contact with devices should be made of antistatic materials.

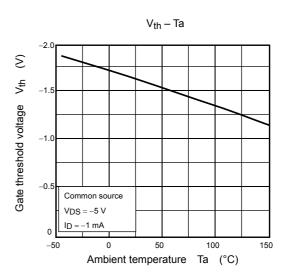




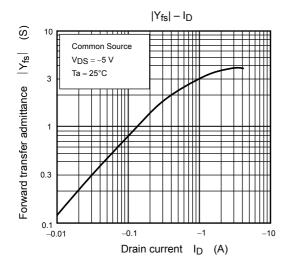


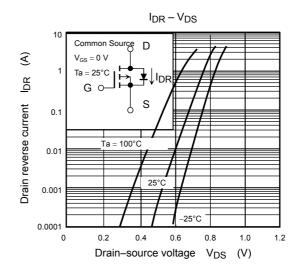


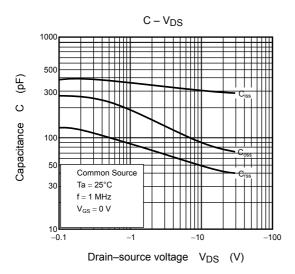


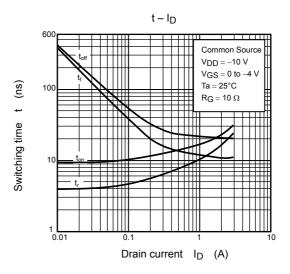


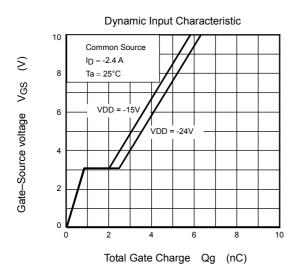
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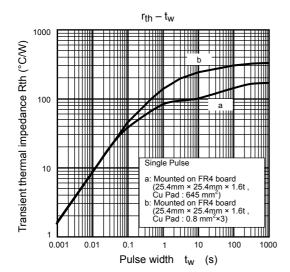


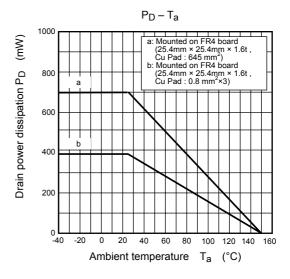












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